

AL 2133 PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 09/697,305

Confirmation No.: 4222

In re Application of:

Takaki YOSHIDA et al.

Group Art Unit: 2133

Filed: October 27, 2000

Examiner: Joseph D. Torres

For: FAULT DETECTING METHOD AND LAYOUT METHOD

FOR SEMICONDUCTOR INTEGRATED CIRCUIT

PETITION UNDER 37 CFR §1.97(d) (2)

Commissioner of Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Applicants hereby respectfully request consideration and entry of the Information Disclosure Statement filed contemporaneously herewith. The reference cited in the Information Disclosure Statement was cited in an Office Action in a corresponding Japanese patent application on September 21, 2004. The certification under Rule 97(e)(1) is filed herewith, as well as a check in the amount of \$180.00, pursuant to Rule 17(i)(1).

Serial No.: 09/697,305

Consideration and entry of the attached Information Disclosure Statement is respectfully requested.

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Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004

Date

Roger W. Parkhurst

Registration No. 25,177

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RWP/mhs

Attachments:

Check No. 1825 for \$180

Certification Under 37 CFR §1.97(e)
Information Disclosure Statement

USPTO-1449

Japanese Patent Appln. No. 09-080121

Attorney Docket No.: YMOR:186

PARKHURST & WENDEL, L.L.P. 1421 Prince Street, Suite 210 Alexandria, VA 22314-2805 Telephone: (703) 739-0220 PLEASE ACCEPT THIS AS AUTHORIZATION TO DEBIT OR CREDIT FEES TO DEP. ACCT. 16-0331 PARKHURST & WENDEL





IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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CERTIFICATION UNDER 37 CFR § 1.97(e)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

[x] Each item of information contained in the Information Disclosure Statement filed herewith was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

OR

[] No item of information in the Information Disclosure Statement filed, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR § 1.56(c) more

Serial No. 09/697,305

than three months prior to the filing of this Information Disclosure Statement.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004

Date

Roger W. Parkhurst

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RWP/mhs

Attorney Docket No.: YMOR:186

Attachment:

Information Disclosure Statement

PARKHURST & WENDEL, L.L.P. 1421 Prince Street, Suite 210 Alexandria, Virginia 22314-2805 Telephone: (703) 739-0220



PATENT

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Takaki YOSHIDA et al. Group Art Unit: 2133

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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the U.S. Patent and Trademark Office is hereby directed to the reference listed on the attached Form PTO-1449. A copy of the reference listed on Form PTO-1449 is attached.

The attached reference, JP 9-80121 was cited in an Office Action dated September 21, 2004 in the corresponding Japanese Application No. 11-307872. The USPTO is directed thereto for a concise statement of possible relevance of the reference cited therein.

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The above information is presented so that the U.S. Patent and Trademark Office may, in the first instance, determine any materiality thereof to the claimed invention. See 37 CFR \$1.104(a) and \$1.106(b) concerning the USPTO duty to consider and use any such information. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004

Date

Roger W. Parkhurst

Registration No. 25,177

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Attorney Docket No.: YMOR:186

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Sheet <u>1</u> of <u>1</u>								
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. YMOR:186 SERIAL 09/697,3			305		
			APPLICANT Takaki YOSHIDA et al. FILING DATE October 27, 2000 GROUP 2133					
			FILING DATE October 27, 2000			GROUP 2133 RADEMARKS		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	CLASS S		FILING DATE IF APPROPRIATE	
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FOREIGN PATENT DOCUMENTS								
	DOCUMENT NUMBER	DATE	COUNTRY		ASS	SUBCLASS	TRANSLATION NO YES	
	09-080121	03/1997	Japan					Partial
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
EVAMINED	L			DATE C	ONSIDER			

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.